Update on $t\bar{t}t\bar{t}$ Searches in Single Lepton/OS Dilepton Channel Using 2016 Data

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Current Status

- Aiming at re-preapproval, documentation -
- We have requested for the production of two new $t\bar{t}$ samples with 9M events each for the two channel(semi-lep and OS dilep), with dedicated cuts at generator level to increase MC stats by a factor of $\backsim$ 10 in high multiplicity/discriminant tails. Details on slide 19
- We are studying the effects of possible background from QCD multi jets with mis-identified leptons.

Data, MC and Objects

Data and MC

- Run2016 B-H, $35.9 pb^{-1}$
- Summer 16 MiniAOD MC for Morond 17
  - signal sample: $t\bar{t}t\bar{t}$ amc@NLO
  - background samples: $t\bar{t}$(backup, mass, width), single $t(\bar{t})$, DY, W+jets, $t\bar{t} + Z/H/W/diboson$

Objects

Single Lepton

- μ : tight ID, $p_T > 26$ GeV, $|\eta| < 2.1$, $RelIso < 0.15$
- e : tight ID, $p_T > 35$ GeV, $|\eta| < 1.4442$ or $1.566 < |\eta| < 2.1$
- jet : loose ID, $p_T > 30$ GeV, $|\eta| < 2.1$, $\Delta R > 0.4$

OS Dilepton

- μ : loose ID, leading(subleading) lep $p_T > 25(20)$ GeV, $|\eta| < 2.4$, $RelIso < 0.15$
- e : loose ID, leading(subleading) lep $p_T > 25(20)$ GeV, $|\eta| < 1.4442$ or $1.566 < |\eta| < 2.4$
- jet : loose ID, $p_T > 30$ GeV(25 GeV if tagged as b), $|\eta| < 2.4$, $\Delta R > 0.4$

Event Selection and MC Re-weighting

Event selection

Single Lepton

- N_l^{tight}=1
- $N_\mu^{loose} = 0, N_e^{veto} = 0$
- $N_j \geq 8(7)$ in $e(\mu)$ channel of which $N_{tags}^M \geq 2$
- $\not{E}_T > 50$ GeV
- $HT \geq 500$ GeV

OS Dilepton

- Exactly 2 OS leptons
- $M_{ll} \geq 106$ GeV or $76 \geq M_{ll} \geq 20$ GeV
- $N_j \geq 4$ of which $N_{tags}^M \geq 2$
- $HT \geq 500$ GeV

MC Re-weighting

- Trigger eff.
- Lepton scales
- Pileup Reweight
- JER/JEC
- b-tagging eff.
- top p_T *reweight*

$t\bar{t}t\bar{t}$ Search Method

Binned analysis fitting on event level BDT

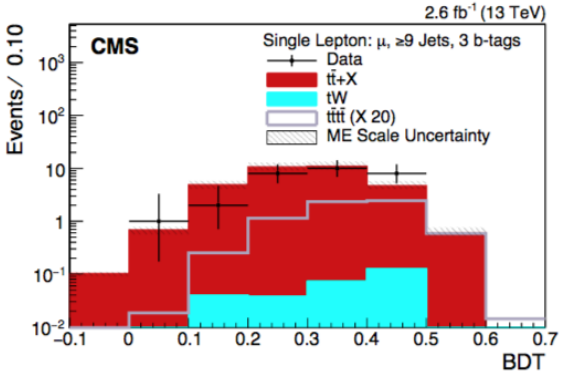


Figure : Single μ event level BDT in $\geq$9 jet 3 btag category

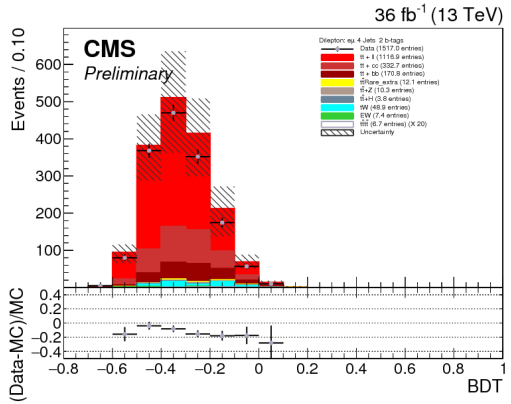


Figure : μe event level BDT in CR

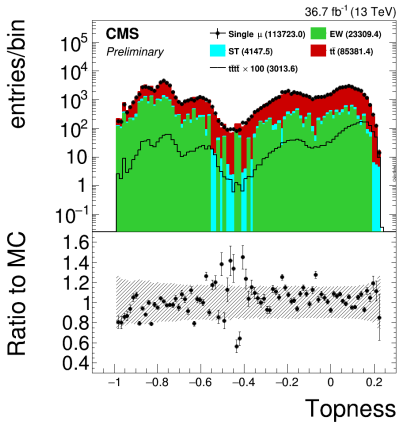
Event categorization in $N_j \otimes N_{tags}^M$ for limit fitting

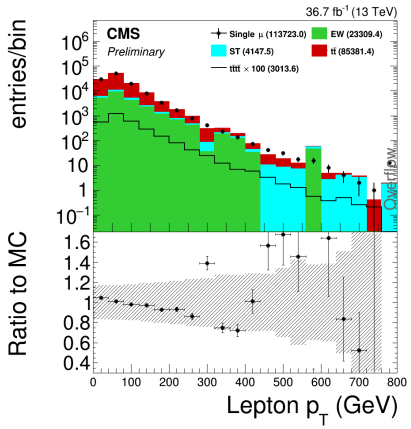
- Single lepton channel
  - μ: N_j: 7, 8, 9, 10+; N_{tags}^M: 2, 3, 4+
  - e: N_j: 8, 9, 10+; N_{tags}^M: 2, 3, 4+
- OS Dilepton channel: N_j: 4-5, 6-7, 8+; N_{tags}^M: 2, 3+

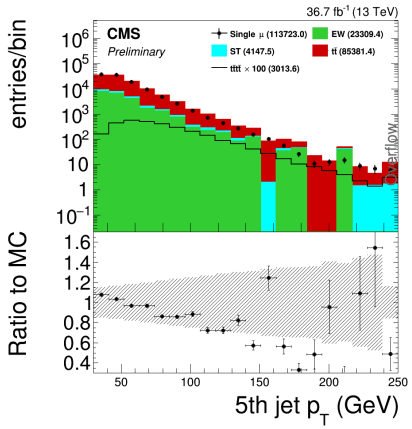
Control Plots (BDT Input Variables)

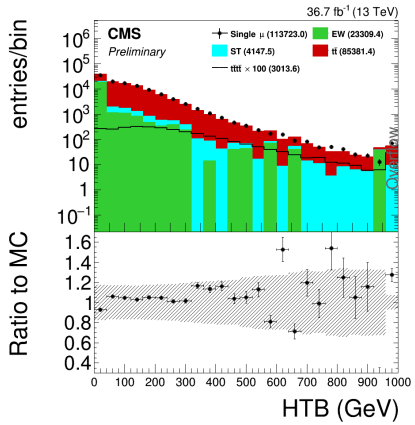
- Single lepton channel

$BDT_{trijet2}$, HTH, H_T^b, H_T^{Rat}, p_T^{5thjet}, p_T^{6thjet}, M_{RE}^H, HT_X, p_T^{lep}, CSV_3, CSV_4, CSV_{3rdjet}, CSV_{4thjet}



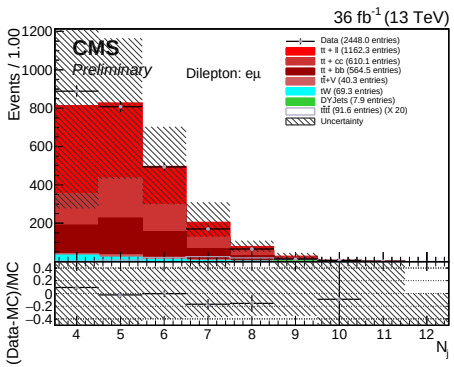


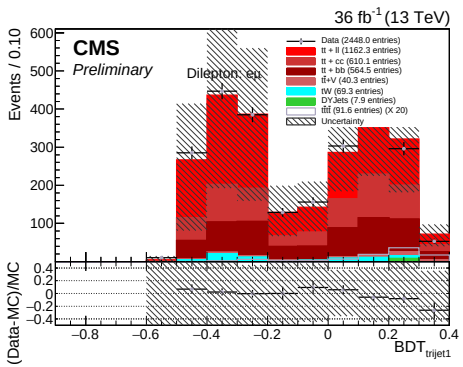


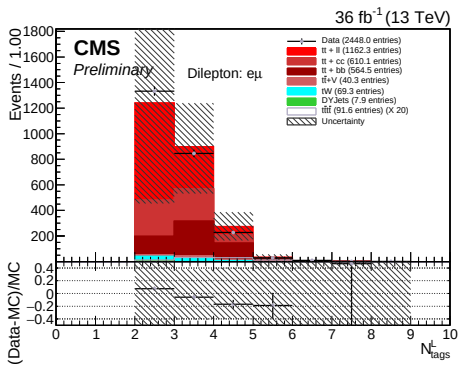


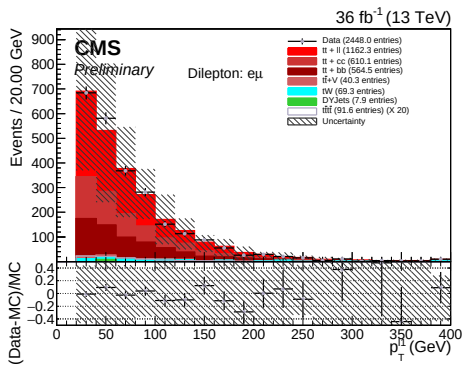
- OS Dilepton channel

N_j, $BDT_{trijet1}$, H_T^b, H_T^{2M}, HTH, S, H_T^{Rat}, p_T^{l1}, η^{l1}, ΔR_{ll}, ΔR_{bb}, N_{tags}^L, N_{tags}^M, p_T^{3rdjet}, p_T^{4thjet}









- Overall reasonable distributions agreement within uncertainties.

Sources of Systematic Uncertainties

Experimental Uncertainties

- Luminosity uncertainty
- Pileup $\pm 1\sigma$
- Lepton SFs uncertainty
- JER $\pm 1\sigma$
- JES(split)
  - SubTotalPileUp
  - SubTotalRelative
  - SubTotalPt
  - SubTotalScale
  - Jet flavor
- b-tag CSV $\pm 1\sigma$
- Heavy flavor fraction
- Top p_T reweight
- Jet normalization

Theoretical Uncertainties

- ME scale
- MC cross sections
- UE tune
- PS scale
- ME-PS matching
- PDF

Fit Strategy

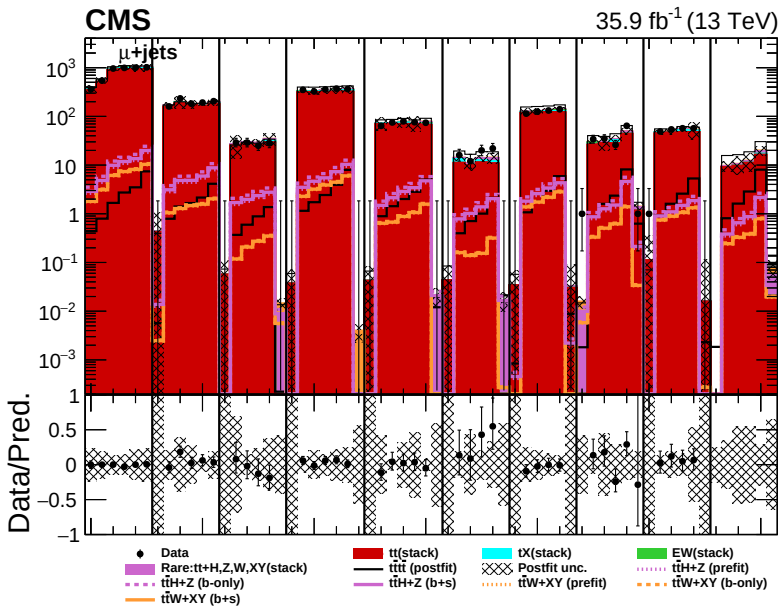
- Likelihood fit using Combine Tool
- Event level BDT output discriminator distributions for fit is performed simultaneously in different $N_j \otimes N_{tags}^M$ categories.
- Blind highest jet/tag multiplicity categories.
  - single lepton: blind 10+ jets & 3+ tags category
  - OS dilepton: blind 8+ jets & 3+ tags category
- Combine results from single lepton channel and OS dilepton channel.

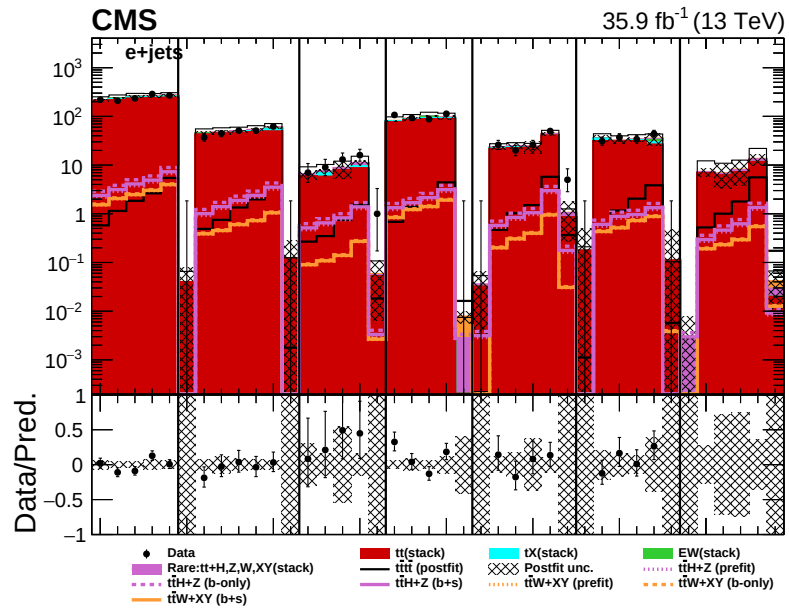
Template Fit in Single Lepton Channel

Table : Single lepton blinded fitting results

Channel	Expected limit $\times \sigma^{SM}_{t\bar{t}t\bar{t}}$	Expected xsec fb	Expected significance
e	$23.5^{+7.0}_{-6.5}$	216.2^{+64}_{-60}	0.09
μ	$16.0^{+7.0}_{-4.7}$	147.2^{+64}_{-43}	0.12
combined	$9.4^{+4.0}_{-2.7}$	86.5^{+37}_{-25}	0.25

Postfit BDT distributions





- Equiprobable binning scheme
- Blind signal rich 10+/3+ category
- Reasonable description of the data in CRs

Fit Diagnostic in Single Lepton Channel

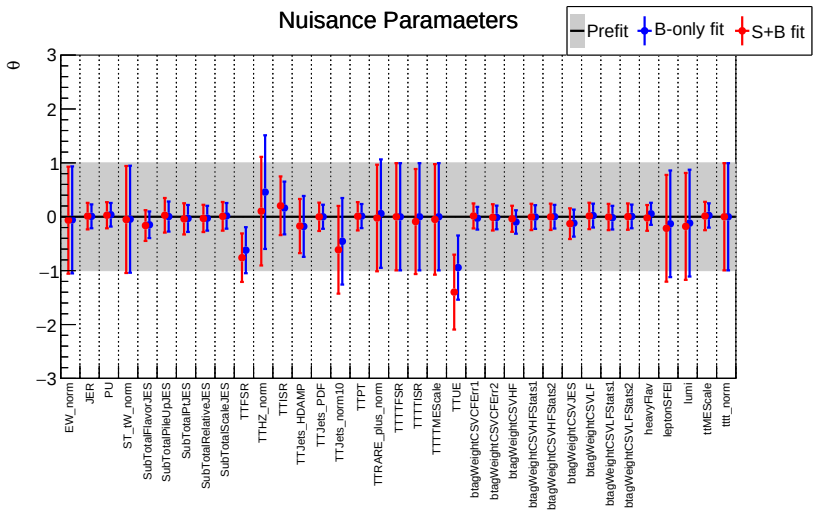


Figure : μ+jets channel

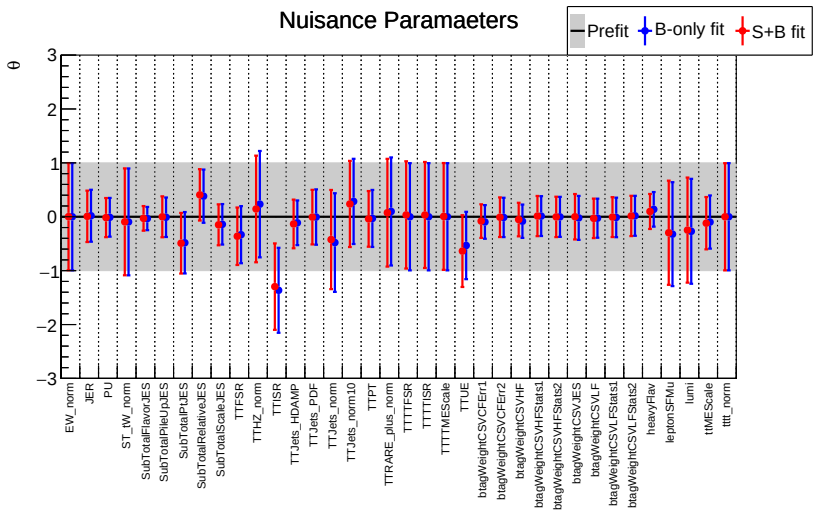
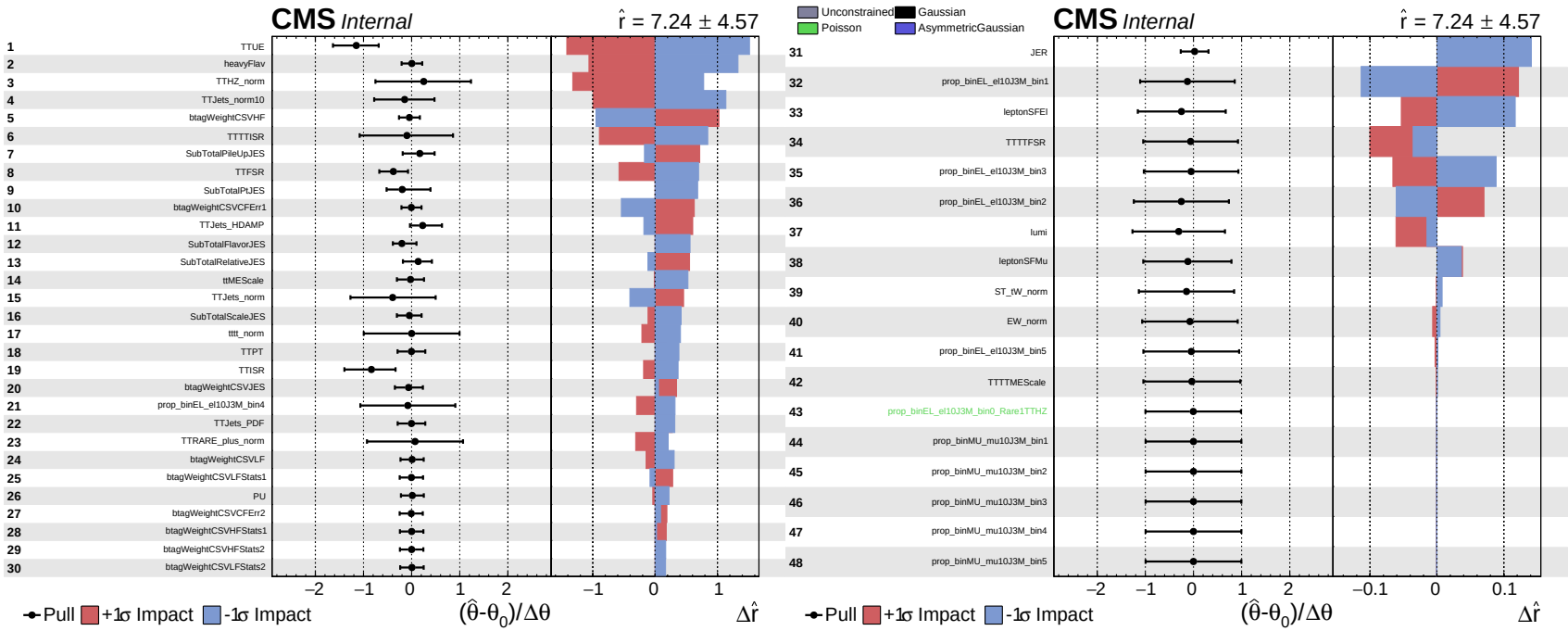


Figure : e+jets channel

- Post-fit uncertainty reduction is under investigation

Impact of Nuisance Parameters



- Dominant sources of systematic uncertainty:
  - UE variation. Affects jet multiplicity spectrum (Sample has low statistics)
  - $t\bar{t}b\bar{b}$ normalization
  - Normalization of $t\bar{t}Z, H \to b\bar{b}$
  - Reweighting of HF component in CSV discriminant

Template Fit in OS Dilepton Channel

Table : OS dilepton blinded fitting results

Channel	Expected limit $\times\sigma^{SM}_{t\bar{t}t\bar{t}}$	Expected limit $\times fb$	Expected significance
$\mu\mu$	$14.56^{+9.64}_{-5.24}$	134^{+89}_{-48}	0.19
$e\mu$	$9.88^{+6.53}_{-3.53}$	91^{+60}_{-32}	0.37
ee	$17.56^{+11.34}_{-6.19}$	162^{+104}_{-57}	0.29
combined	$6.88^{+4.44}_{-2.42}$	63^{+41}_{-22}	0.52

Highest region blinded postfit BDT distributions

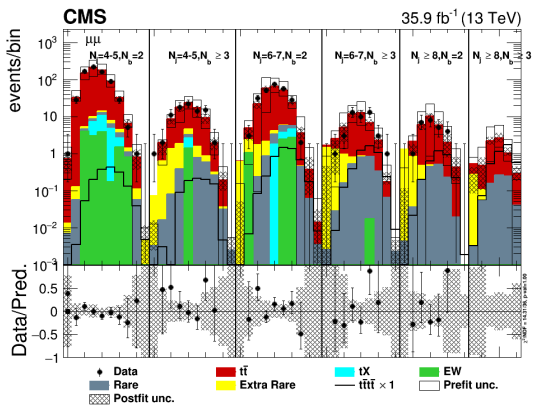


Figure : $\mu\mu$ channel

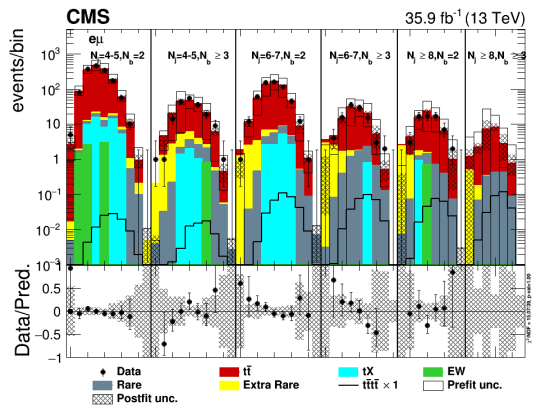


Figure : $e\mu$ channel

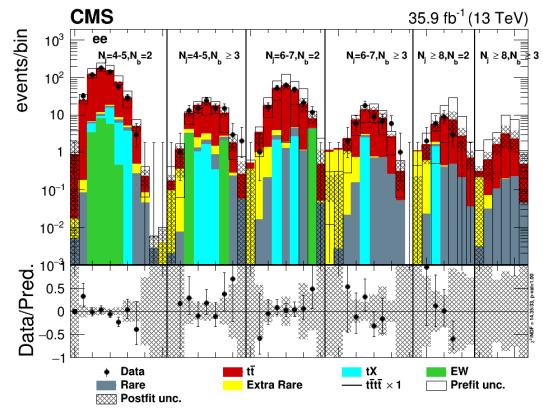


Figure : ee channel

Fit Diagnostic in OS Dilepton Channel

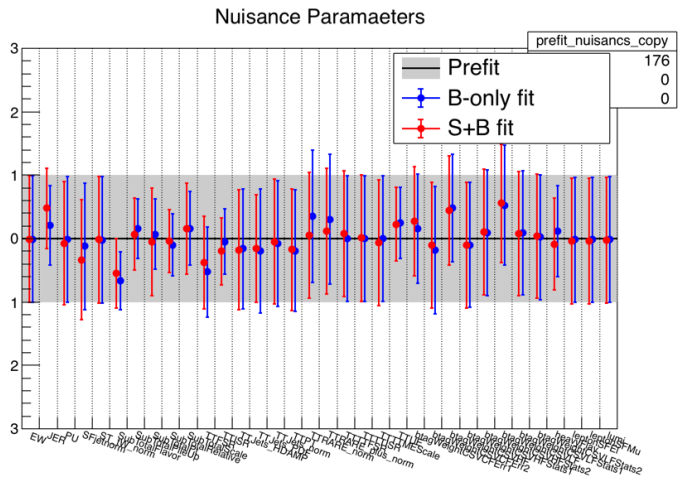


Figure : nuisance pulls in $\mu\mu$

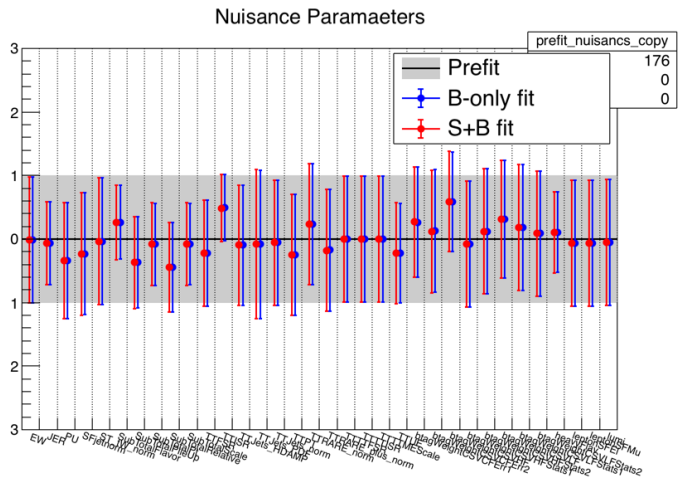


Figure : nuisance pulls in $e\mu$

- Most signal sensitive region is blinded
- No extreme pulls or constraints.
- Reasonable behavior for all the NPs
- Results are consistent between three sub-channels

Fit Diagnostic in OS Dilepton Channel

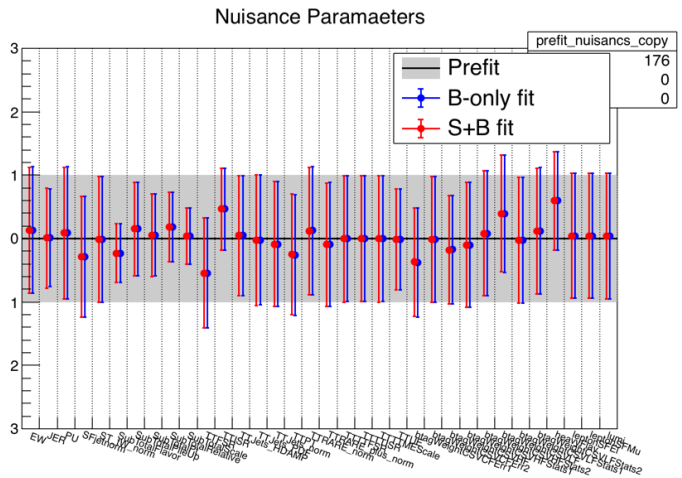


Figure : nuisance pulls in *ee*

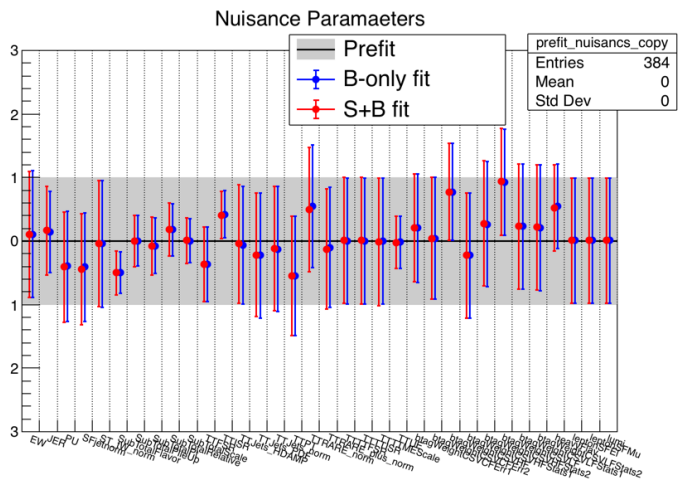


Figure : nuisance pulls in OS dilep

- Mainly the sub-components of JES are constrained
  - Statistic fluctuation
  - Correlated with other NPs

Nuisance Parameters with highest impact in OS dilep combined fit

- Signal systematics and TTRare have the largest impacts, as we are very close to the expected signal strength.
- Jet energy scale uncertainties and MC stats in signal enriched bins dominate.
- All nuisance parameters behave reasonably.
- Full list of nuisance impacts are on backup slides 21 to 22

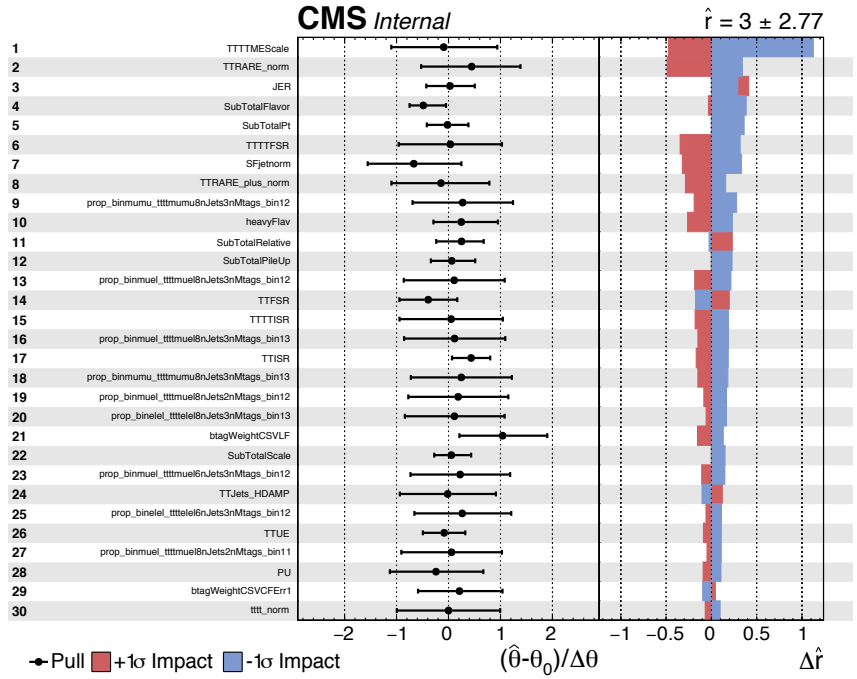


Figure : Impact of nuisance parameters on the parameter of interest

Combined Results

Table : Single lepton + OS dilepton blinded combined results

Channel	Expected limit $\times \sigma^{SM}_{t\bar{t}t\bar{t}}$	Expected limit $\times fb$	Expected significance
l+jets	$9.4^{+4.0}_{-2.7}$	86.5^{+37}_{-25}	0.25
OS ll+jets	$6.9^{+4.4}_{-2.4}$	63^{+41}_{-22}	0.52
combined	$5.2^{+2.6}_{-1.7}$	48^{+24}_{-16}	0.58

- Signal sensitivity is driven by the OS *ll*+jets channel

Conslusion

Backups

Filter optimized for l+jets channel

- Preferred configuration: $HT > 500$, $\mathrm{nJets} + \mathrm{nLep} \geq 9$, $\mathrm{nLep} = 1$ (9M)

		Acceptance loss in different jet multiplicity regions[1]		
Filter cuts	Filter eff.	SL ($N_J^{rec} = 9$)	SL ($N_J^{rec} > 9$)	Ext ($\times 10$)
HT>500 nJets+nLep $\geq$8 1 lepton	0.005 ± 0.0002	0.11	0.08	21.8 M
HT > 500 nJets+nLep $\geq$ 9 1 lepton	0.002 ± 0.0001	0.19	0.10	8.7M
HT>500 nJets+nLep>=10 1 lepton	$0.0007 \pm 6.5 \times 10^{-5}$	—	0.19	3M

[1] Fraction of events passing offline cuts but rejected by gen filter

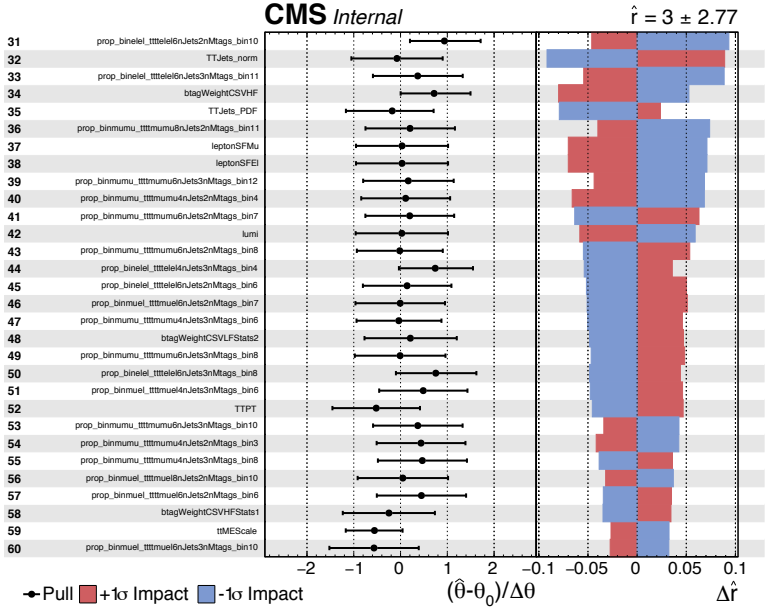
Filter optimized for OS dilpeton channel

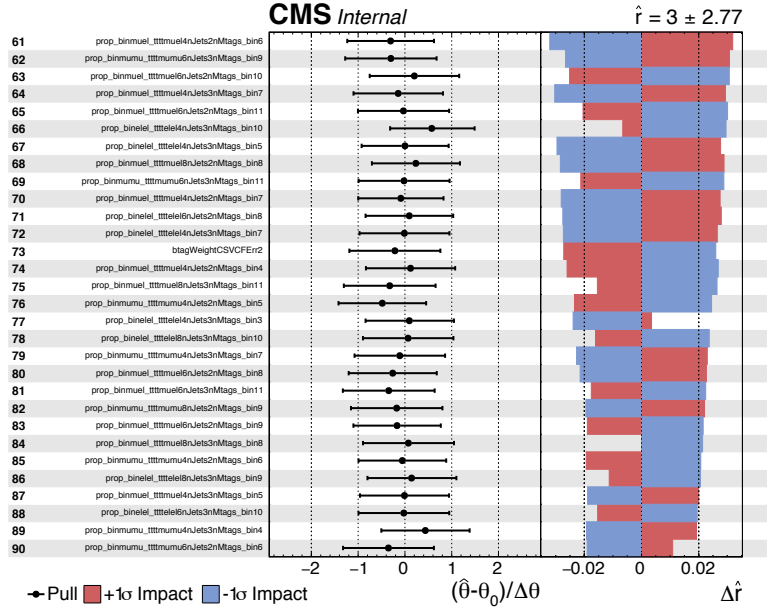
- Preferred configuration: $HT > 500$, $\mathrm{nJets} + \mathrm{nLep} \geq 7$, $\mathrm{nLep} = 2$ (9M)

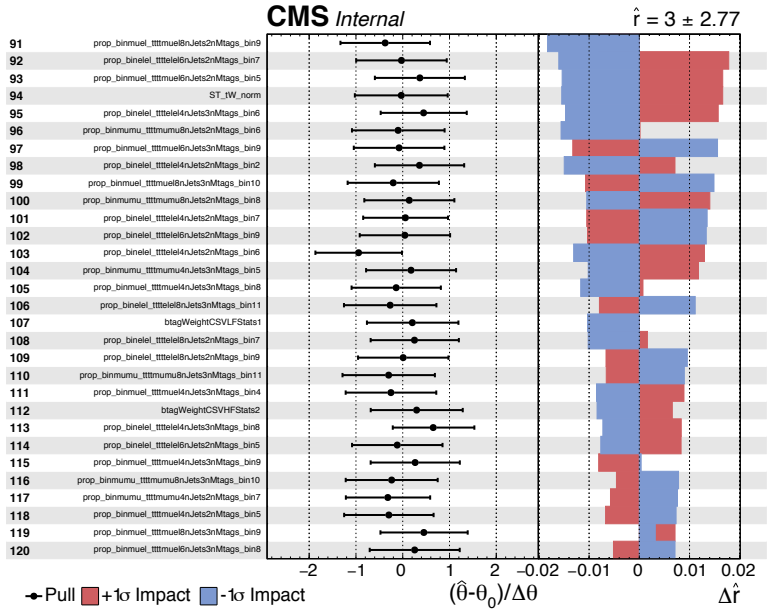
		Acceptance loss in different jet multiplicity regions[2]		
Filter cuts	Filter eff.	OS ($N_J^{rec} = 7$)	OS ($N_J^{rec} \geq 8$)	Ext ($\times 10$)
HT>500 nJets+nLep>=5 2 lepton	$0.0046 \pm 5.5e-05$	0.21	0.23	20 M
HT>500 nJets+nLep>=6 2 lepton	$0.0033 \pm 4.7e-05$	0.21	0.23	14.4 M
HT>500 nJets+nLep>=7 2 lepton	$0.0020 \pm 3.6e-05$	0.23	0.24	8.7 M
HT>500 nJets+nLep>=8 2 lepton	$0.0009 \pm 2.4e-05$	0.31	0.25	3.9 M

[2] Fraction of events passing offline cuts but rejected by gen filter

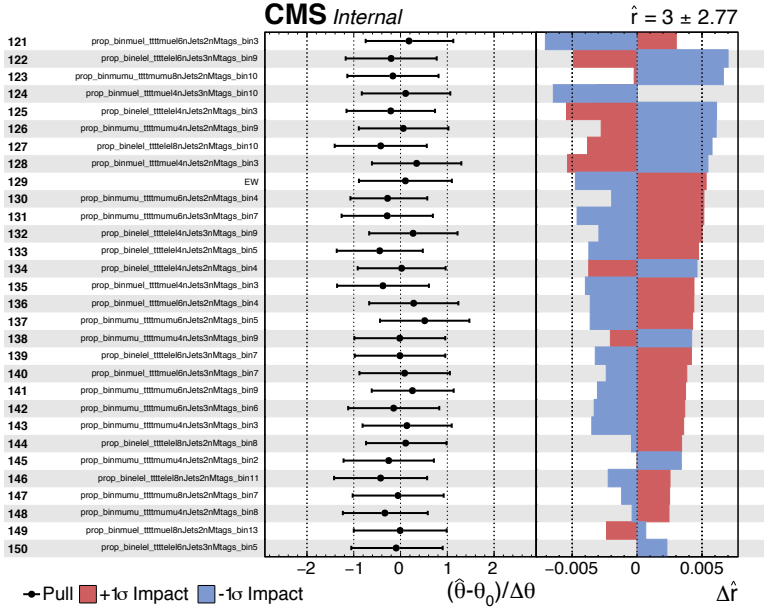
impacts of nuisance parameters

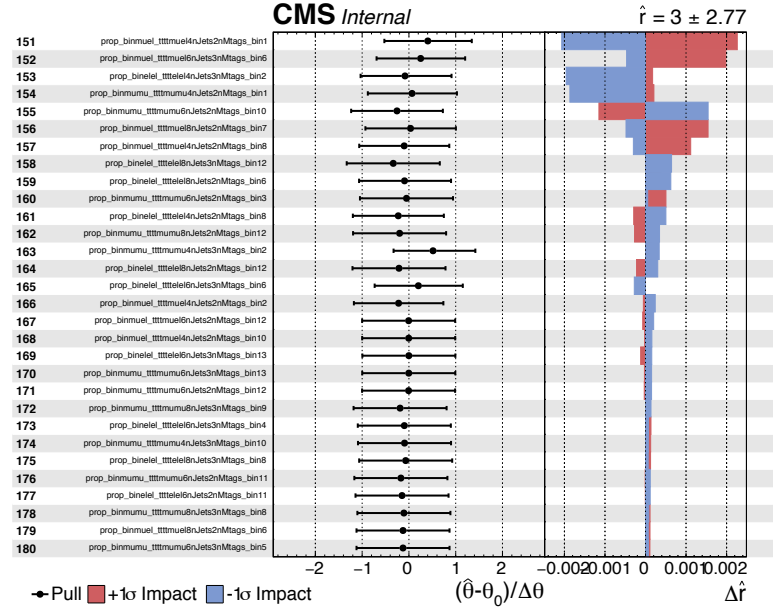


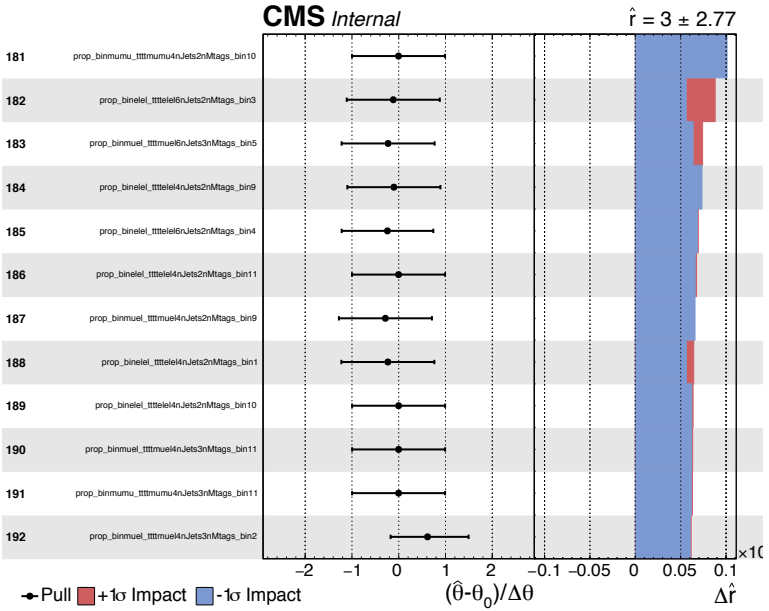




impacts of nuisance parameters







Maybe some more control plots?